### **DISCRETE SEMICONDUCTORS**

# DATA SHEET

# BF1101; BF1101R; BF1101WR N-channel dual-gate MOS-FETs

Product specification Supersedes data of 1999 Feb 01



### N-channel dual-gate MOS-FETs

BF1101; BF1101R; BF1101WR

#### **FEATURES**

- Short channel transistor with high forward transfer admittance to input capacitance ratio
- Low noise gain controlled amplifier up to 1 GHz
- Partly internal self-biasing circuit to ensure good cross-modulation performance during AGC and good DC stabilization.

#### **APPLICATIONS**

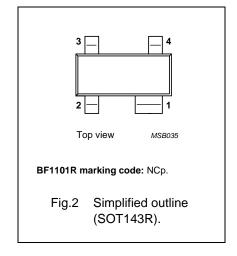
 VHF and UHF applications with 3 to 7 V supply voltage, such as television tuners and professional communications equipment.

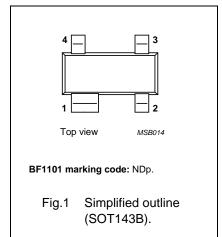
#### **DESCRIPTION**

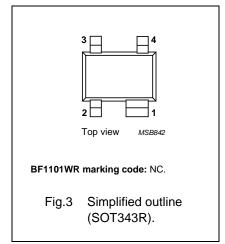
Enhancement type N-channel field-effect transistor with source and substrate interconnected. Integrated diodes between gates and source protect against excessive input voltage surges. The BF1101, BF1101R and BF1101WR are encapsulated in the SOT143B, SOT143R and SOT343R plastic packages respectively.

#### **PINNING**

PIN	DESCRIPTION
1	source
2	drain
3	gate 2
4	gate 1







#### **QUICK REFERENCE DATA**

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
V <sub>DS</sub>	drain-source voltage		_	_	7	V
I <sub>D</sub>	drain current		_	_	30	mA
P <sub>tot</sub>	total power dissipation		_	_	200	mW
y <sub>fs</sub>	forward transfer admittance		25	30	_	mS
C <sub>ig1-ss</sub>	input capacitance at gate 1		-	2.2	2.7	pF
C <sub>rss</sub>	reverse transfer capacitance	f = 1 MHz	_	25	35	fF
F	noise figure	f = 800 MHz	-	1.7	2.5	dB
X <sub>mod</sub>	cross-modulation	input level for k = 1% at 40 dB AGC	100	_	_	dBμV
Tj	operating junction temperature		_	_	150	°C

### **CAUTION**

This product is supplied in anti-static packing to prevent damage caused by electrostatic discharge during transport and handling.

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#### **LIMITING VALUES**

In accordance with the Absolute Maximum Rating System (IEC 134).

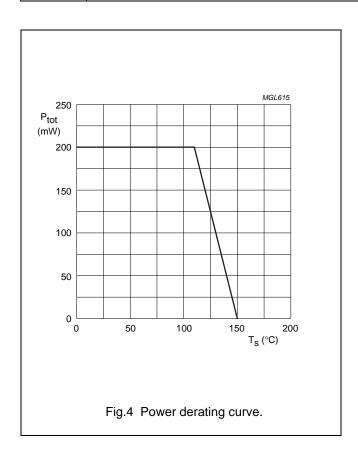
SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V <sub>DS</sub>	drain-source voltage		_	7	V
I <sub>D</sub>	drain current		_	30	mA
I <sub>G1</sub>	gate 1 current		_	±10	mA
I <sub>G2</sub>	gate 2 current		_	±10	mA
P <sub>tot</sub>	total power dissipation	T <sub>s</sub> ≤ 110 °C; note 1	_	200	mW
T <sub>stg</sub>	storage temperature		-65	+150	°C
Tj	operating junction temperature		_	+150	°C

### Note

1.  $T_s$  is the temperature of the soldering point of the source lead.

#### THERMAL CHARACTERISTICS

SYMBOL	PARAMETER	VALUE	UNIT
R <sub>th j-s</sub>	thermal resistance from junction to soldering point	200	K/W



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#### STATIC CHARACTERISTICS

 $T_i = 25$  °C unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V <sub>(BR)DSS</sub>	drain-source breakdown voltage	$V_{G1-S} = V_{G2-S} = 0; I_D = 10 \mu A$	7	_	V
V <sub>(BR)G1-SS</sub>	gate 1-source breakdown voltage	$V_{G2-S} = V_{DS} = 0$ ; $I_{G1-S} = 10 \text{ mA}$	7	16	V
V <sub>(BR)G2-SS</sub>	gate 2-source breakdown voltage	$V_{G1-S} = V_{DS} = 0$ ; $I_{G2-S} = 10 \text{ mA}$	7	16	V
V <sub>(F)S-G1</sub>	forward source-gate 1 voltage	$V_{G2-S} = V_{DS} = 0; I_{S-G1} = 10 \text{ mA}$	0.5	1.5	V
V <sub>(F)S-G2</sub>	forward source-gate 2 voltage	$V_{G1-S} = V_{DS} = 0$ ; $I_{S-G2} = 10 \text{ mA}$	0.5	1.5	V
V <sub>G1-S (th)</sub>	gate 1-source threshold voltage	$V_{G2-S} = 4 \text{ V}; V_{DS} = 5 \text{ V}; I_D = 100 \mu\text{A}$	0.3	1.0	V
V <sub>G2-S (th)</sub>	gate 2-source threshold voltage	$V_{G1-S} = 5 \text{ V}; V_{DS} = 5 \text{ V}; I_D = 100 \mu\text{A}$	0.3	1.2	V
I <sub>DSX</sub>	drain-source current	$V_{G2-S} = 4 \text{ V}; V_{DS} = 5 \text{ V}; R_{G1} = 120 \text{ k}\Omega;$ note 1	8	16	mA
I <sub>G1-SS</sub>	gate 1 cut-off current	$V_{G2-S} = V_{DS} = 0; V_{G1-S} = 5 V$	-	50	nA
I <sub>G2-SS</sub>	gate 2 cut-off current	V <sub>G1-S</sub> = V <sub>DS</sub> = 0; V <sub>G2-S</sub> = 4 V	_	20	nA

#### Note

1.  $R_{G1}$  connects  $G_1$  to  $V_{GG} = 5$  V; see Fig.21.

#### **DYNAMIC CHARACTERISTICS**

Common source;  $T_{amb} = 25$  °C;  $V_{G2-S} = 4$  V;  $V_{DS} = 5$  V;  $I_D = 12$  mA; unless otherwise specified.

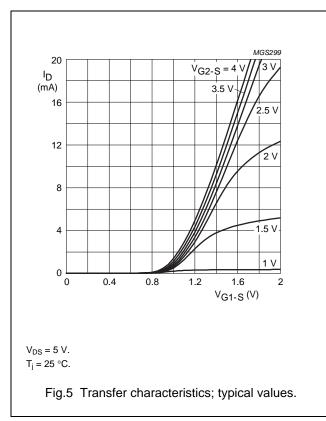
SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
y <sub>fs</sub>	forward transfer admittance	pulsed; T <sub>j</sub> = 25 °C	25	30	40	mS
C <sub>ig1-ss</sub>	input capacitance at gate 1	f = 1 MHz	_	2.2	2.7	pF
C <sub>ig2-ss</sub>	input capacitance at gate 2	f = 1 MHz	_	1.6	_	pF
C <sub>oss</sub>	output capacitance	f = 1 MHz	_	1.2	_	pF
C <sub>rss</sub>	reverse transfer capacitance	f = 1 MHz	_	25	35	fF
F	noise figure	$f = 800 \text{ MHz}; Y_S = Y_{S \text{ opt}}$	_	1.7	2.5	dB
X <sub>mod</sub>	cross-modulation	input level for k = 1% at 0 dB AGC; f <sub>w</sub> = 50 MHz; f <sub>unw</sub> = 60 MHz; note 1	85	_	_	dBμV
		input level for k = 1% at 40 dB AGC; f <sub>w</sub> = 50 MHz; f <sub>unw</sub> = 60 MHz; note 1	100	_	_	dBμV

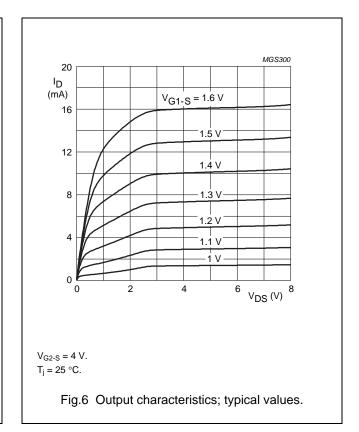
### Note

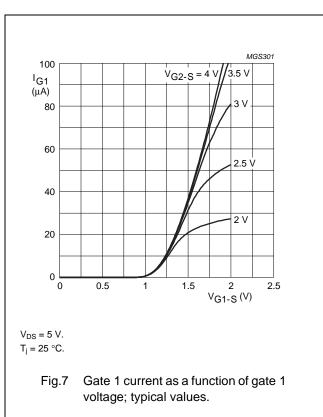
1. Measured in test circuit of Fig.21.

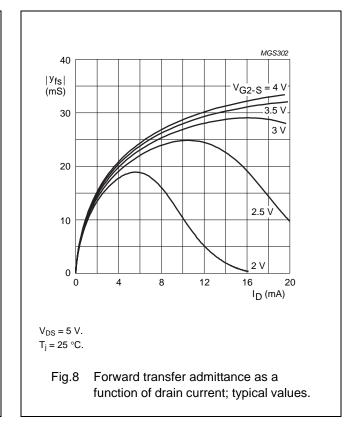
### N-channel dual-gate MOS-FETs

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### N-channel dual-gate MOS-FETs

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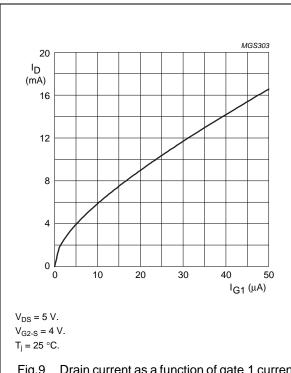
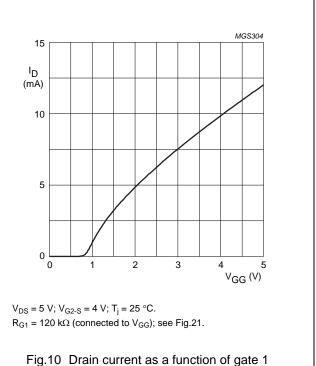
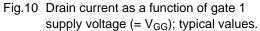
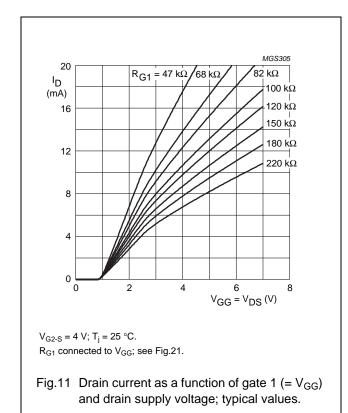


Fig.9 Drain current as a function of gate 1 current; typical values.



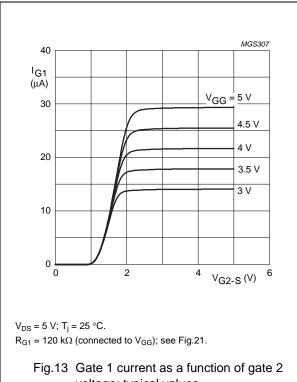




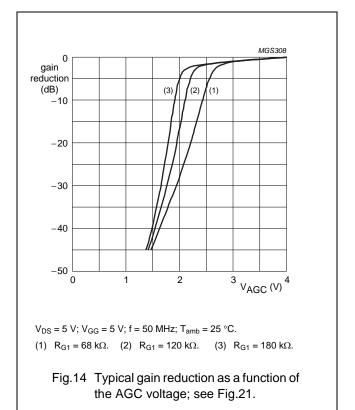
MGS306 16 V<sub>GG</sub> = 5 V  $I_D$ (mA) 4.5 V 12 4 V 3.5 V 3 V 8 0 V<sub>G2-S</sub> (V)  $V_{DS} = 5 \text{ V}; T_j = 25 \text{ }^{\circ}\text{C}.$  $R_{G1}$  = 120  $k\Omega$  (connected to  $V_{GG});$  see Fig.21. Fig.12 Drain current as a function of gate 2 voltage; typical values.

### N-channel dual-gate MOS-FETs

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voltage; typical values.



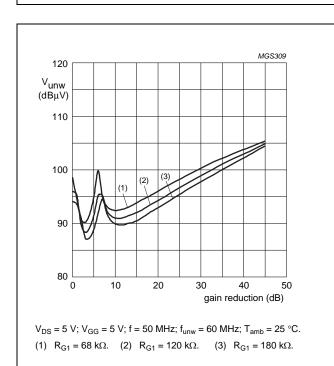
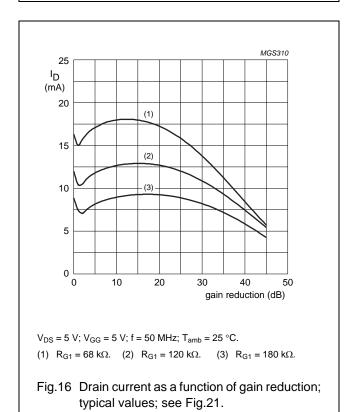


Fig.15 Unwanted voltage for 1% cross-modulation as a function of gain reduction; typical values; see Fig.21.



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### N-channel dual-gate MOS-FETs

### BF1101; BF1101R; BF1101WR

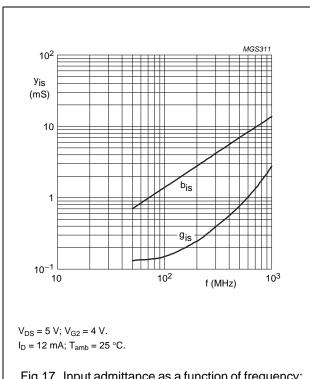


Fig.17 Input admittance as a function of frequency; typical values.

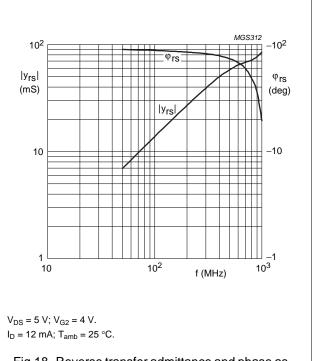
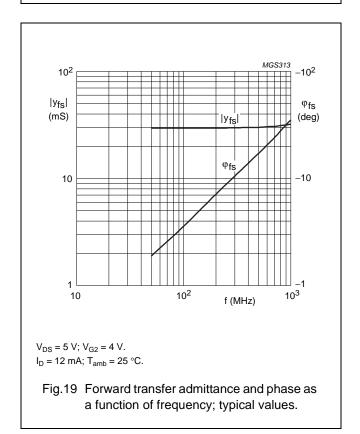
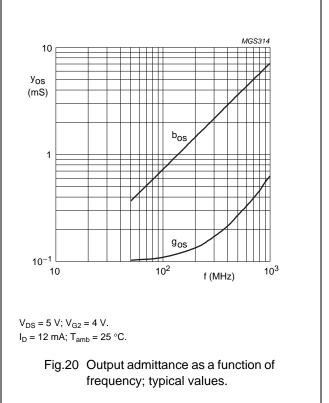


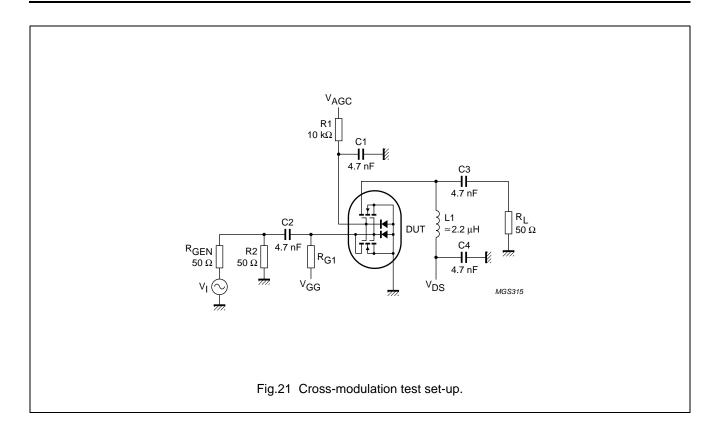
Fig.18 Reverse transfer admittance and phase as a function of frequency; typical values.





## N-channel dual-gate MOS-FETs

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**Table 1** Scattering parameters:  $V_{DS} = 5 \text{ V}$ ;  $V_{G2-S} = 4 \text{ V}$ ;  $I_D = 12 \text{ mA}$ ;  $T_{amb} = 25 ^{\circ}\text{C}$ 

f	S <sub>11</sub>		S <sub>21</sub>		S <sub>12</sub>		S <sub>22</sub>	
(MHz)	MAGNITUDE (ratio)	ANGLE (deg)	MAGNITUDE (ratio)	ANGLE (deg)	MAGNITUDE (ratio)	ANGLE (deg)	MAGNITUDE (ratio)	ANGLE (deg)
50	0.987	-4.1	2.922	175.0	0.001	87.6	0.990	-2.2
100	0.985	-8.1	2.908	170.3	0.001	86.1	0.989	-4.3
200	0.976	-16.1	2.875	160.8	0.003	83.3	0.985	-8.5
300	0.963	-23.9	2.820	157.6	0.004	80.4	0.982	-12.6
400	0.949	-31.6	2.762	142.6	0.005	78.2	0.977	-16.8
500	0.933	-38.8	2.665	134.1	0.005	77.8	0.972	-20.8
600	0.916	-45.7	2.591	125.7	0.005	78.9	0.967	-24.7
700	0.897	-52.2	2.498	117.7	0.006	81.8	0.961	-28.5
800	0.877	-58.4	2.410	109.6	0.005	89.1	0.957	-32.2
900	0.856	-64.5	2.318	101.6	0.006	97.1	0.950	-35.8
1000	0.832	-70.3	2.214	94.2	0.006	110.4	0.946	-39.6

**Table 2** Noise data:  $V_{DS} = 5 \text{ V}$ ;  $V_{G2-S} = 4 \text{ V}$ ;  $I_D = 12 \text{ mA}$ ;  $T_{amb} = 25 ^{\circ}\text{C}$ 

f	F <sub>min</sub>	Γ	R <sub>n</sub>	
(MHz)	(dB)	(ratio)	(deg)	<b>(</b> Ω <b>)</b>
800	1.5	0.715	58.3	37.85

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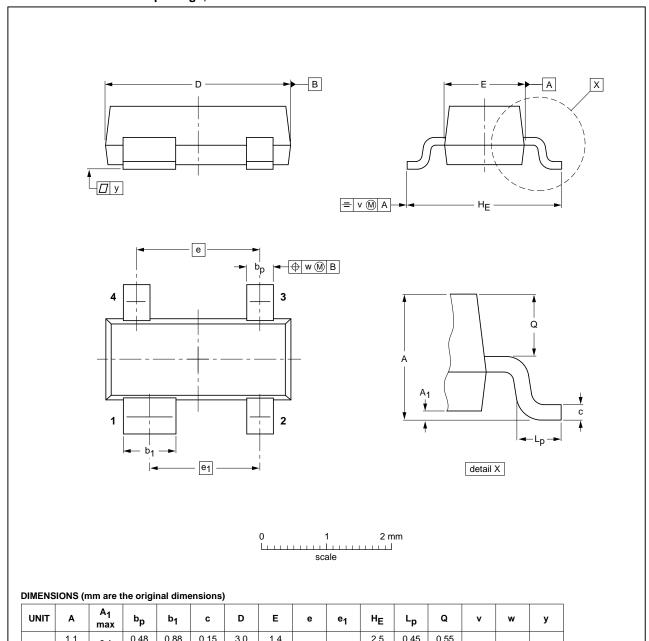
# N-channel dual-gate MOS-FETs

# BF1101; BF1101R; BF1101WR

#### **PACKAGE OUTLINES**

### Plastic surface-mounted package; 4 leads

SOT143B



ı	JNIT	Α	A <sub>1</sub> max	bp	b <sub>1</sub>	С	D	E	е	e <sub>1</sub>	HE	Lp	Q	v	w	у
	mm	1.1 0.9	0.1	0.48 0.38	0.88 0.78	0.15 0.09	3.0 2.8	1.4 1.2	1.9	1.7	2.5 2.1	0.45 0.15	0.55 0.45	0.2	0.1	0.1

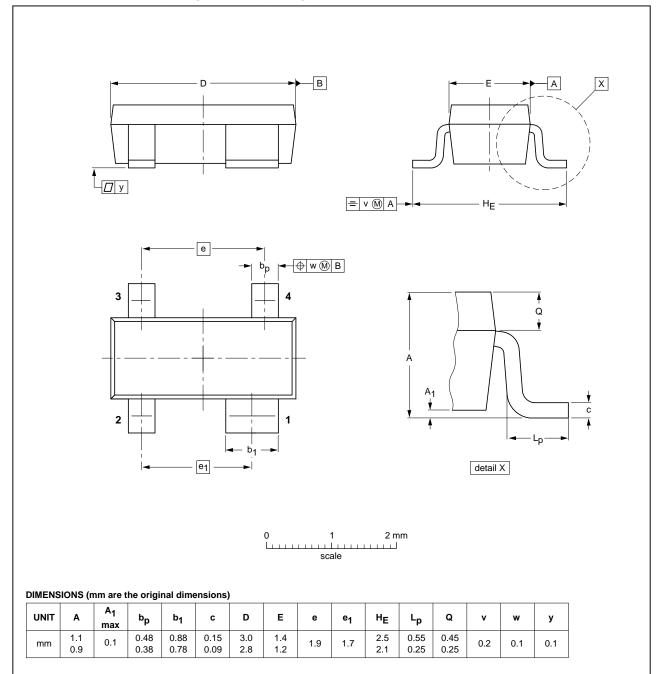
OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE	
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE
SOT143B						<del>-04-11-16</del> 06-03-16

# N-channel dual-gate MOS-FETs

## BF1101; BF1101R; BF1101WR

### Plastic surface-mounted package; reverse pinning; 4 leads

### SOT143R



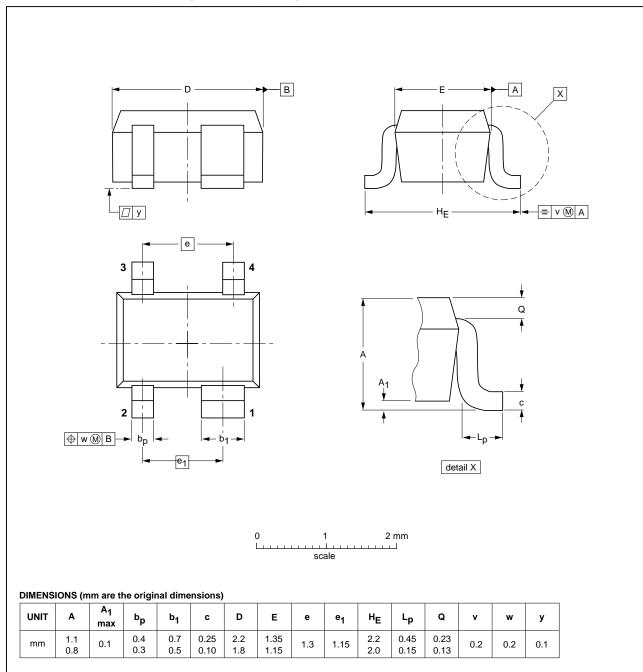
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VERSION	IEC	JEDEC	JEITA		PROJECTION	1990E DATE	
SOT143R			SC-61AA			<del>-04-11-16-</del> 06-03-16	

# N-channel dual-gate MOS-FETs

## BF1101; BF1101R; BF1101WR

### Plastic surface-mounted package; reverse pinning; 4 leads

SOT343R



OUTLINE		REFER	EUROPEAN	ISSUE DATE		
VERSION	IEC	JEDEC	EIAJ		PROJECTION 1880	ISSUE DATE
SOT343R						<del>97-05-21</del> 06-03-16

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### N-channel dual-gate MOS-FETs

BF1101; BF1101R; BF1101WR

#### **DATA SHEET STATUS**

DOCUMENT STATUS <sup>(1)</sup>	PRODUCT STATUS <sup>(2)</sup>	DEFINITION
Objective data sheet	Development	This document contains data from the objective specification for product development.
Preliminary data sheet	Qualification	This document contains data from the preliminary specification.
Product data sheet	Production	This document contains the product specification.

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UF28100M MW6S010GNR1 MW6S010GNR1 DU2820S SD2943W SD2932BW SD2941-10W MRF24301HR5 ARF469AG
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MRFE6VP61K25NR6 MRFE6VP5300NR1 A2T27S020NR1 UF2840P MMRF1304NR1 MRFE6S9060GNR1 MMRF1008GHR5
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